

Fig.1

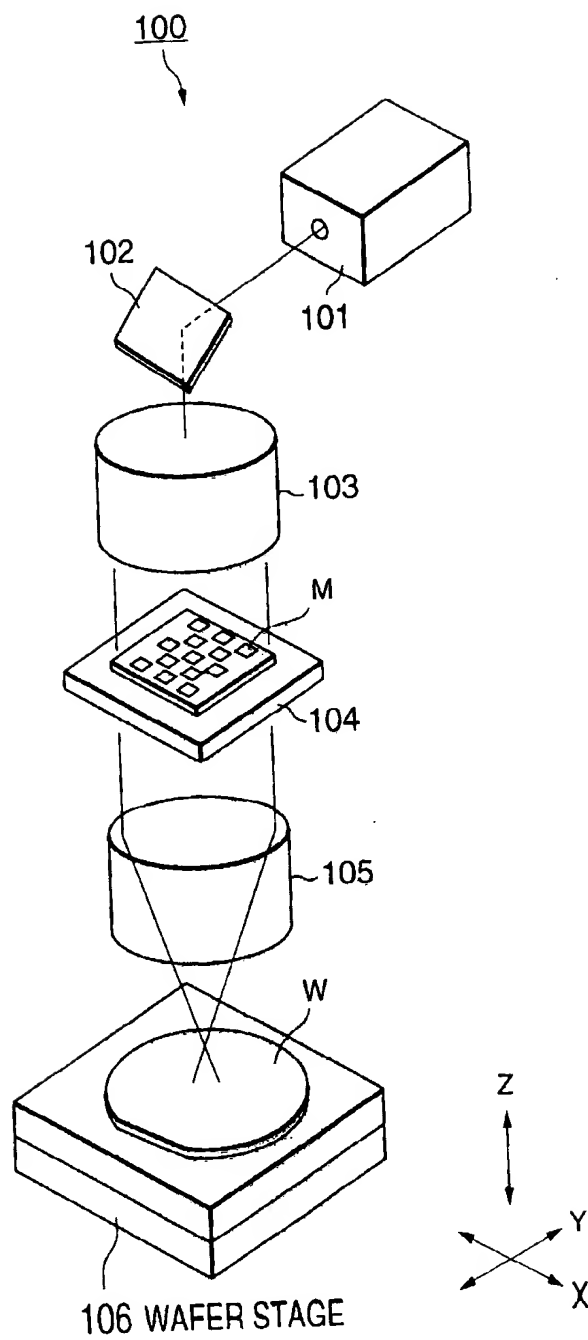
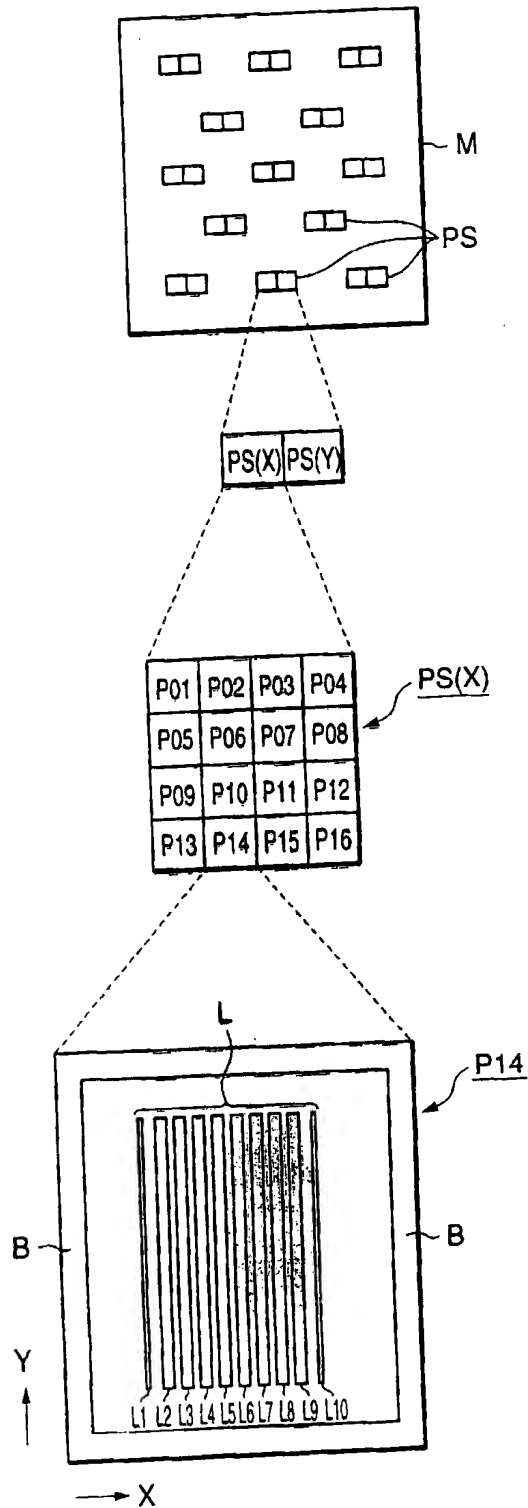


Fig.2



"20160727" 216T8650

Fig.3(a)

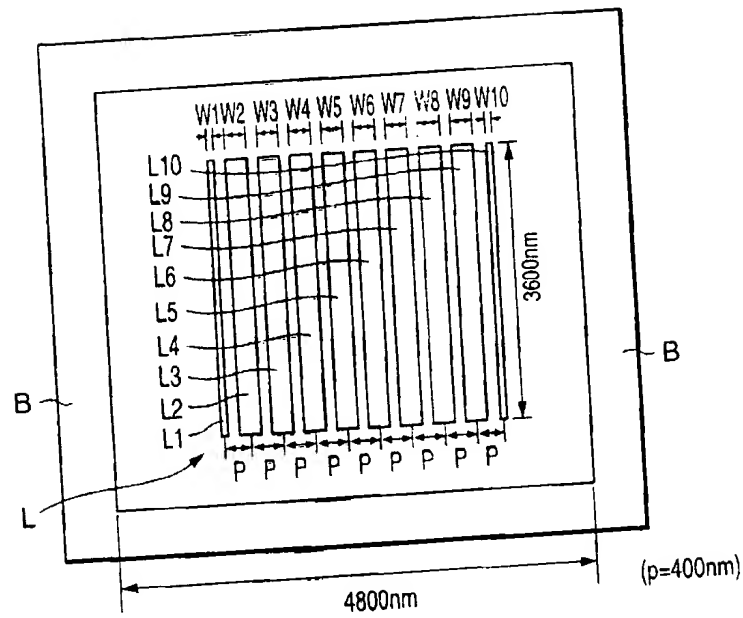
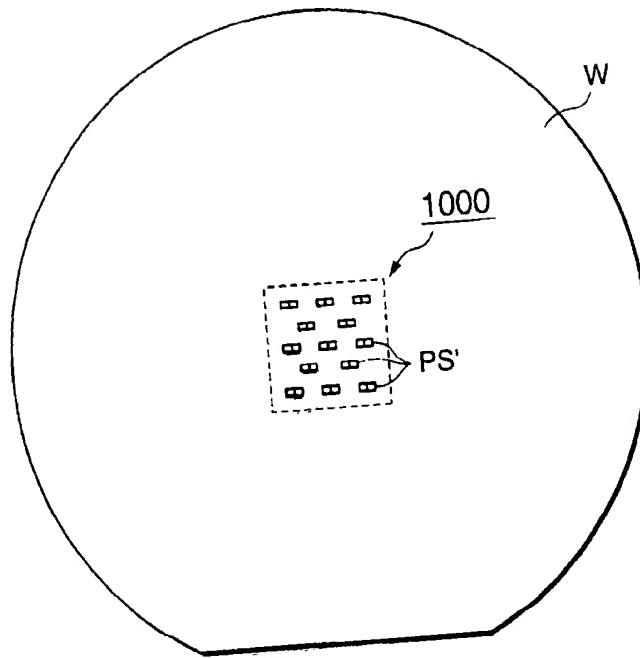


Fig.3(b)

		P02	P03	P04	
	W1, W10 =200nm	" " =195nm	" " =190nm	" " =185nm	
P01					
P06	"	"	"	"	P07
P05	" =180nm	" =175nm	" =170nm	" =165nm	P08
P10	"	"	"	"	P11
P09	" =160nm	" =155nm	" =150nm	" =145nm	P12
P13	"	"	"	"	P16
	" =140nm	" =135nm	" =130nm	" =125nm	
		P14	P15		

Fig.4



TOP SECRET

TOP SECRET

Fig.5(a)

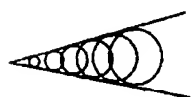


Fig.5(b)

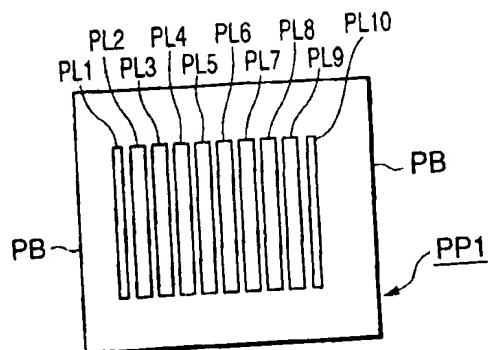


Fig.5(c)

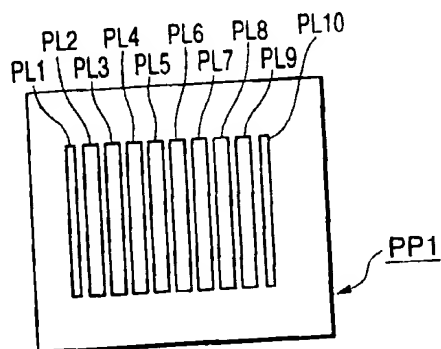


Fig.5(d)

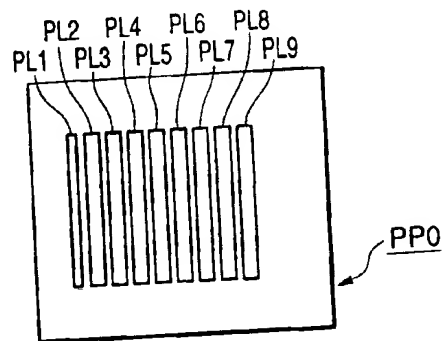


Fig.5(e)

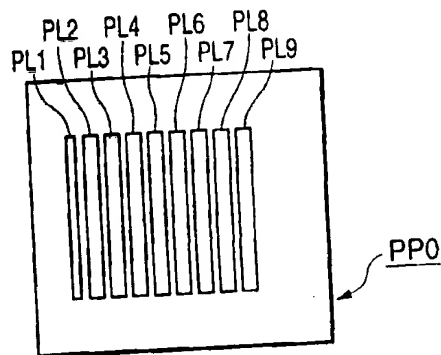


Fig.6(a)

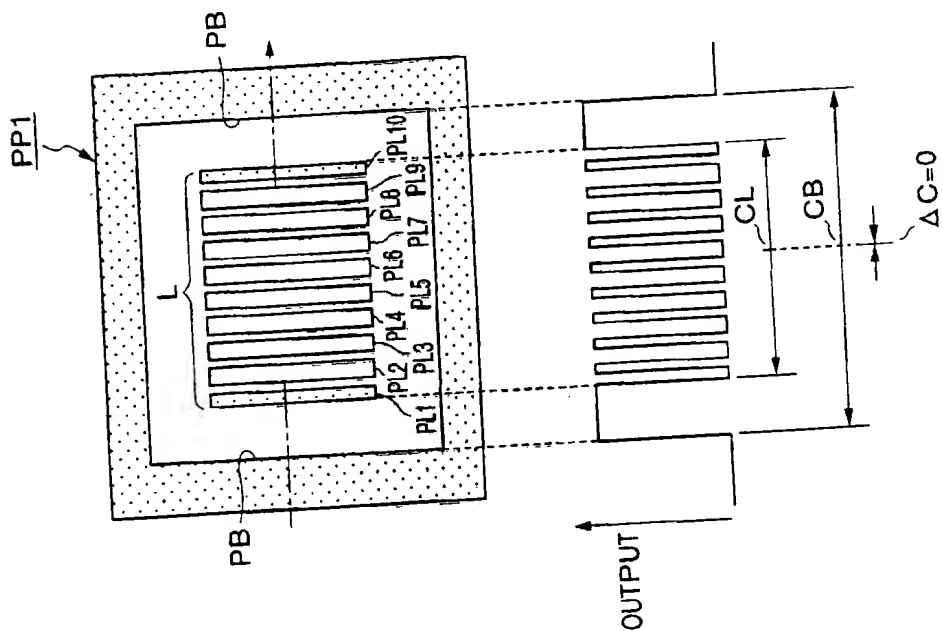


Fig.6(b)

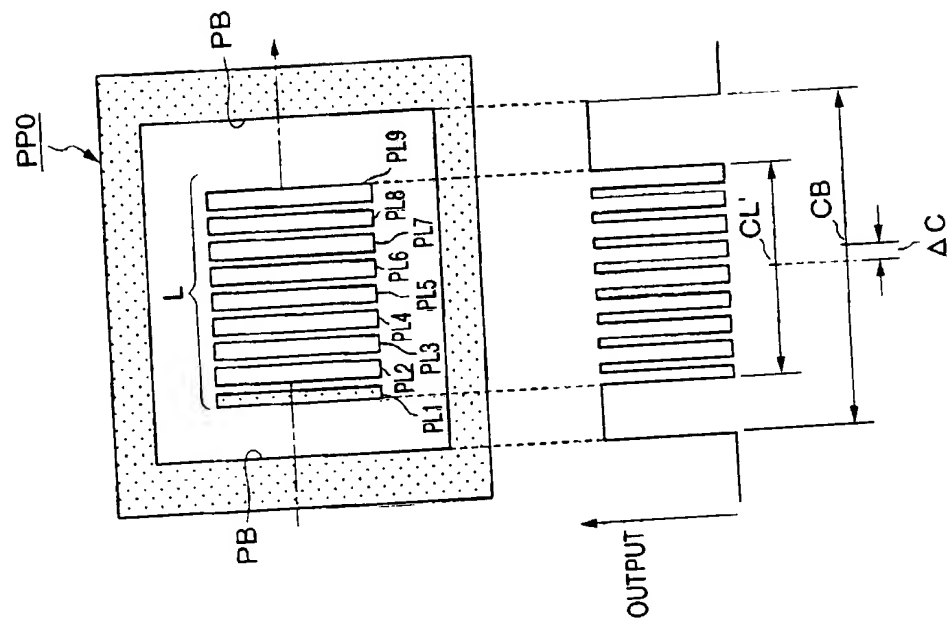


Fig.7

RELATIVE POSITIONAL DEVIATION  
(RESULT OF OVERLAY MEASUREMENT)

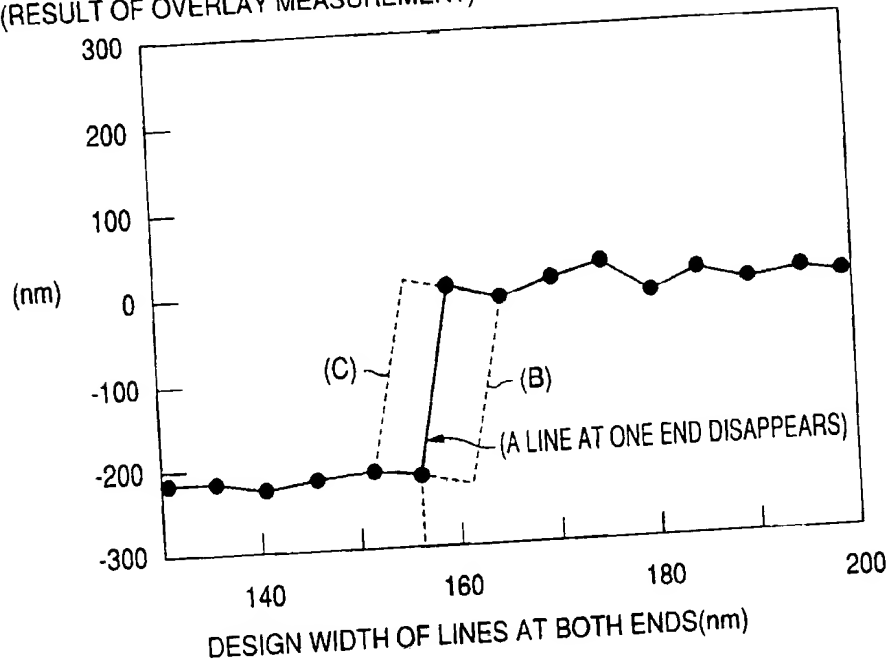


Fig.8

LINE WIDTH RELATED TO A MISSING  
LINE PATTERN AT ONE END

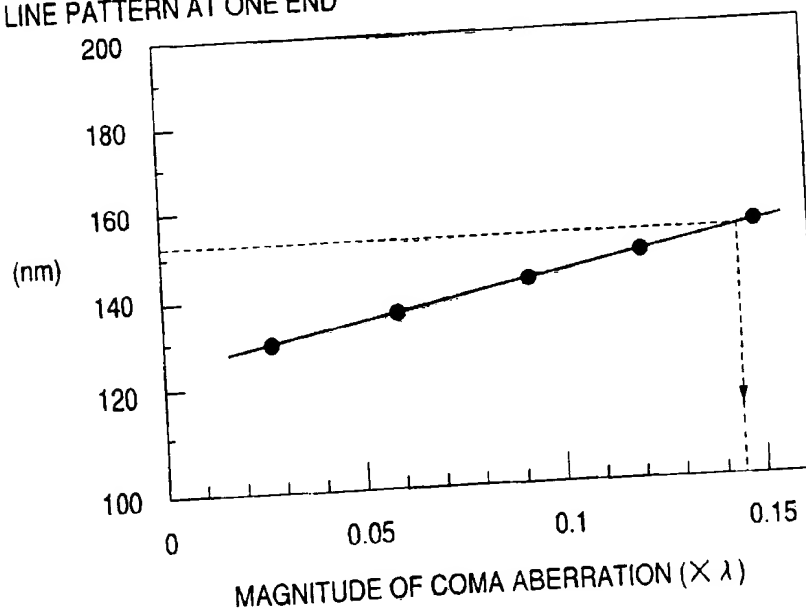
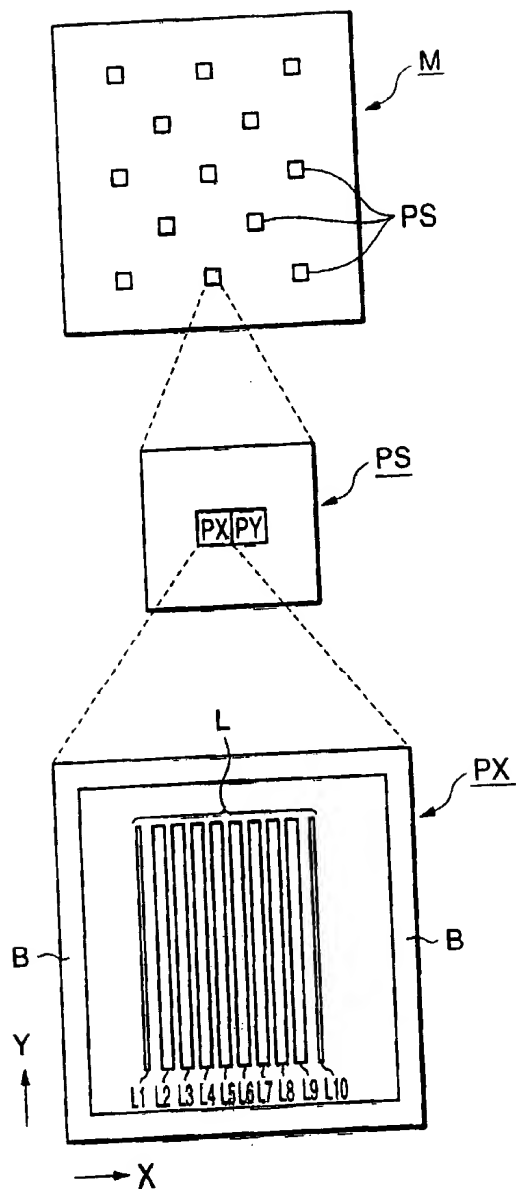


Fig.9



FOOT "2T8660



FIG. 10(a) 216T8660

Fig.10(a)

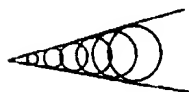


Fig.10(b)

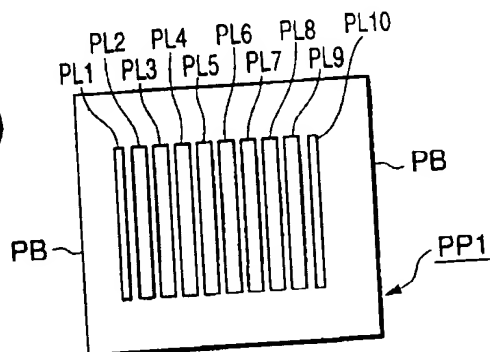


Fig.10(c)

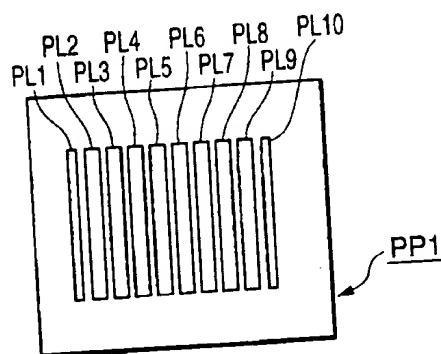


Fig.10(d)

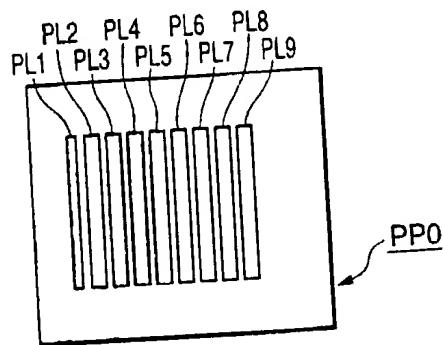


Fig.10(e)

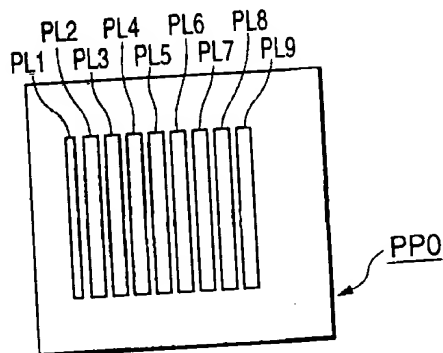


Fig.11

RELATIVE POSITIONAL DEVIATION  
(RESULT OF OVERLAY MEASUREMENT)

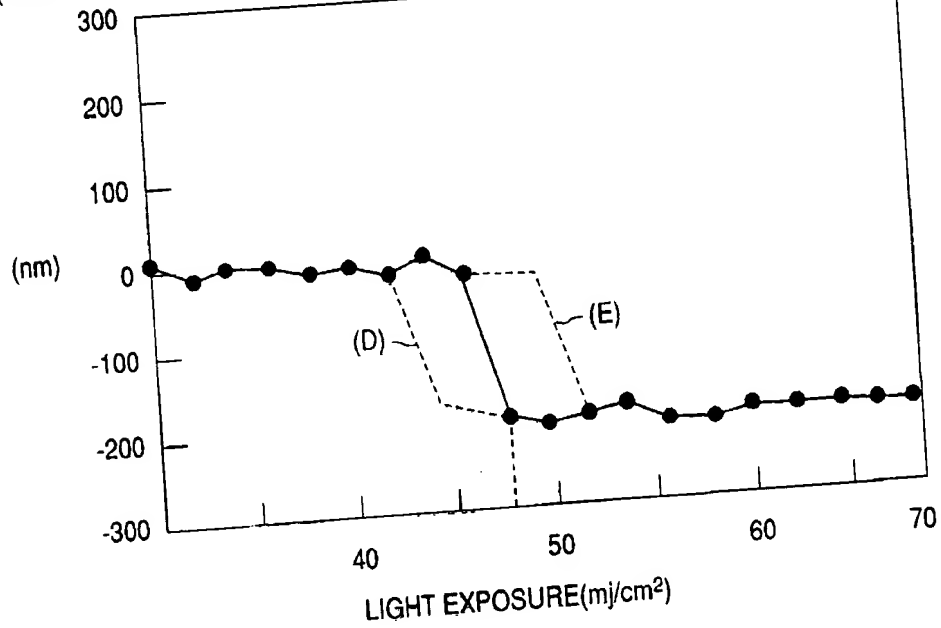


Fig.12

RIGHT EXPOSURE RELATED TO A MISSING  
LINE PATTERN AT ONE END

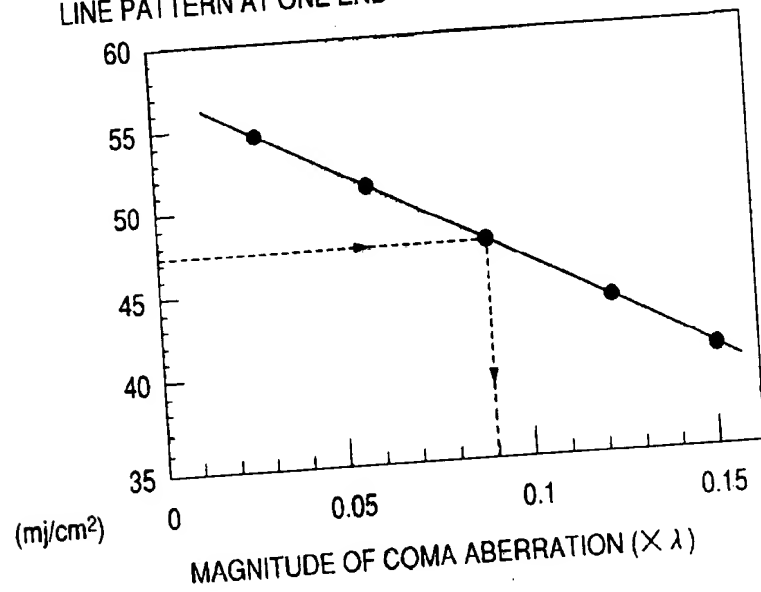


Fig.13(a)

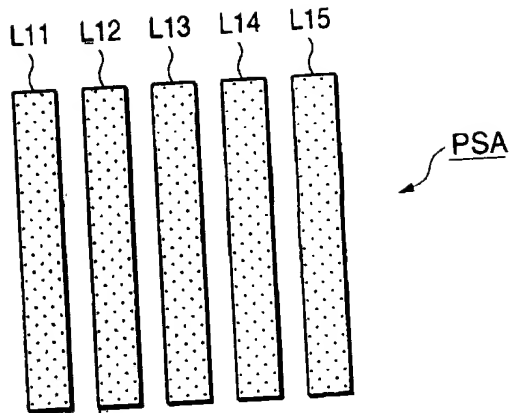


Fig.13(b)

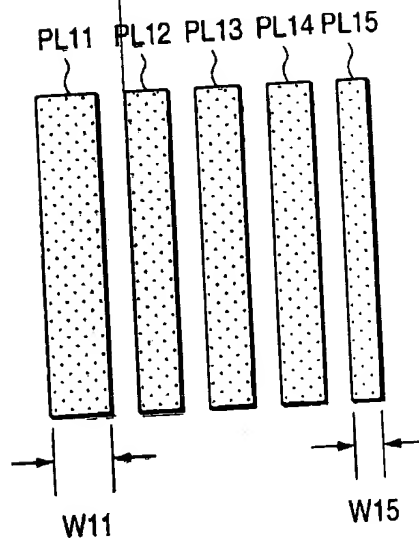


FIG. 13(a) and 13(b)